

## Panel 3

### Best Methods for At-Speed Testing?

#### Abstract

At-speed testing is needed to screen defects that are not screened by stuck-at tests or IDDQ tests. As clocking frequencies increase (200, 400, 600, >600 MHz), detecting defects that prevent fast clocking becomes more important. What are the best methods for screening these defects? This panel and attendees will attempt to answer this question.

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